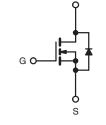


Power MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	200				
R _{DS(on)} (Ω)	$V_{GS} = 5.0 V$	0.18			
Q _g (Max.) (nC)	66				
Q _{gs} (nC)	9.0				
Q _{gd} (nC)	38				
Configuration	Single				





N-Channel MOSFET

FEATURES

- Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- Logic-Level Gate Drive
- R_{DS(on)} Specified at V_{GS} = 4 V and 5 V
- Fast Switching
- · Ease of Paralleling
- Simple Drive Requirements
- Lead (Pb)-free Available

DESCRIPTION

Third generation Power MOSFETs from Vishay provides the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost effectiveness.

The TO-220 package is universally preferred for all commercial-industrial applications at power dissipation levels to approximately 50 W. The low thermal resistance and low package cost of the TO-220 contribute to its wide acceptance throughout the industry.

ORDERING INFORMATION	
Package	TO-220
Lead (Pb)-free	IRL640PbF
	SiHL640-E3
SnPb	IRL640
	SiHL640

ABSOLUTE MAXIMUM RATINGS $T_C = 25 ^{\circ}C$, unless otherwise noted							
PARAMETER			SYMBOL	LIMIT	UNIT		
Drain-Source Voltage		V _{DS}	200	v			
Gate-Source Voltage			V _{GS}	± 10	v		
Continuous Drain Current	V _{GS} at 5.0 V	T _C = 25 °C	- I _D -	17			
		$T_C = 100 ^{\circ}C$		11	A		
Pulsed Drain Current ^a			I _{DM}	68			
Linear Derating Factor			1.0	W/°C			
Single Pulse Avalanche Energy ^b			E _{AS}	580	mJ		
Repetitive Avalanche Current ^a			I _{AR}	10	А		
Repetitive Avalanche Energy ^a			E _{AR}	13	mJ		
Maximum Power Dissipation	T _C = 25 °C		P _D 125		W		
Peak Diode Recovery dV/dt ^c			dV/dt	5.0	V/ns		
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to + 150	°C			
Soldering Recommendations (Peak Temperature)	for	10 s		300 ^d	U		
Mounting Torque	6-32 or M3 screw			10	lbf ⋅ in		
				1.1	N · m		

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

b. V_{DD} = 50 V, starting T_J = 25 °C, L = 3.0 mH, R_G = 25 Ω I_{AS} = 17 A (see fig. 12).

c. $I_{SD} \leq 17$ A, $dI/dt \leq 150$ A/µs, $V_{DD} \leq V_{DS}, \, T_J \leq 150$ °C.

d. 1.6 mm from case.

* Pb containing terminations are not RoHS compliant, exemptions may apply



THERMAL RESISTANCE RA	rings							
PARAMETER	SYMBOL	TYP. MAX.			UNIT			
Maximum Junction-to-Ambient	R _{thJA}	- 62 0.50 -						
Case-to-Sink, Flat, Greased Surface	R _{thCS}				°C/W			
Maximum Junction-to-Case (Drain)	R _{thJC}	- 1.0				1		
		· · ·						
SPECIFICATIONS $T_J = 25 \text{ °C},$		1				I		T
PARAMETER	SYMBOL	TEST	CONDIT	ONS	MIN.	TYP.	MAX.	UNIT
Static						1	1	1
Drain-Source Breakdown Voltage	V _{DS}) V, I _D = 2		200	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference			-	0.27	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_D = 250 \ \mu A$			1.0	-	2.0	V
Gate-Source Leakage	I _{GSS}	$V_{GS} = \pm 10$			-	-	± 100	nA
Zero Gate Voltage Drain Current	Inco	V _{DS} = 2	$V_{DS} = 200 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$			-	25	μA
	IDSS	V _{DS} = 160 V, V	$V_{DS} = 160 \text{ V}, \text{ V}_{GS} = 0 \text{ V}, \text{ T}_{J} = 125 ^{\circ}\text{C}$			-	250	μ
Drain-Source On-State Resistance	Brach	$V_{GS} = 5.0 V$		I _D = 10 A ^b	-	-	0.18	Ω
	R _{DS(on)}	$V_{GS} = 4.0 V$	I	_D = 8.5 A ^b	-	-	0.27	52
Forward Transconductance	g fs	$V_{DS} = \xi$	50 V, I _D =	= 10 A ^b	16	-	-	S
Dynamic								
Input Capacitance	C _{iss}	١	/ _{GS} = 0 V	,	-	1800	-	
Output Capacitance	C _{oss}	V _{DS} = 25 V f = 1.0 MHz, see fig. 5		-	400	-	pF	
Reverse Transfer Capacitance	C _{rss}			-	120	-		
Total Gate Charge	Qg			-	-	66	nC	
Gate-Source Charge	Q _{gs}	$V_{GS} = 5.0 V$	$= 17 \text{ A}, \text{V}_{\text{DS}} = 160 \text{ V},$	-	-	9.0		
Gate-Drain Charge	Q _{gd}	see fig. 6 and 13 ^b		-	-	38		
Turn-On Delay Time	t _{d(on)}		1		-	8.0	-	1
Rise Time	t _r	V_{DD} = 100 V, I _D = 17 A R _G = 4.6 Ω, R _D = 5.7 Ω, see fig. 10 ^b		-	83	-	ns	
Turn-Off Delay Time	t _{d(off)}			-	44	-		
Fall Time	t _f			-	52	-		
Internal Drain Inductance	L _D	Between lead, 6 mm (0.25") from package and center of die contact		-	4.5	-	nH	
Internal Source Inductance	L _S			-	7.5	-		
Drain-Source Body Diode Characteristic	s							
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	17	A	
Pulsed Diode Forward Currenta	I _{SM}			-	-	68		
Body Diode Voltage	V_{SD}	$T_{J} = 25 \text{ °C}, I_{S} = 17 \text{ A}, V_{GS} = 0 \text{ V}^{b}$			-	-	2.0	V
Body Diode Reverse Recovery Time	t _{rr}	- T _J = 25 °C, I _F = 17 A, dl/dt = 100 A/μs ^b		-	310	470	ns	
Body Diode Reverse Recovery Charge	Q _{rr}			-	3.2	4.8	μC	
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L_{S} and L_{D})						L _D)

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

b. Pulse width \leq 300 µs; duty cycle \leq 2 %.



TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

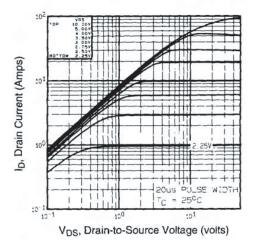


Fig. 1 - Typical Output Characteristics, T_C = 25 °C

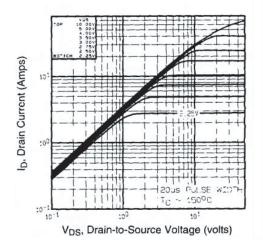


Fig. 2 - Typical Output Characteristics, $T_C = 150$ °C

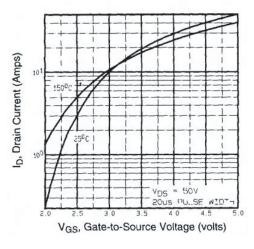


Fig. 3 - Typical Transfer Characteristics

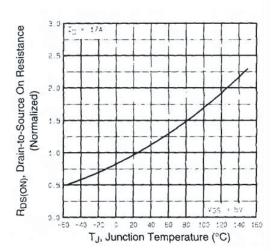


Fig. 4 - Normalized On-Resistance vs. Temperature

IRL640, SiHL640

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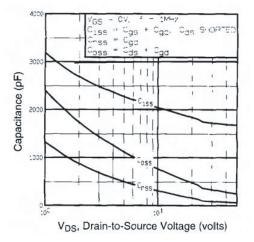


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

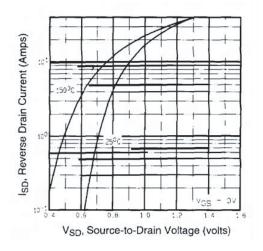


Fig. 7 - Typical Source-Drain Diode Forward Voltage

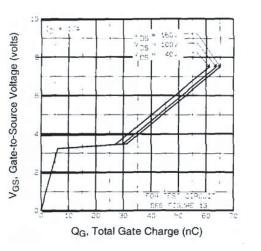


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

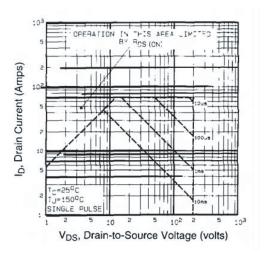
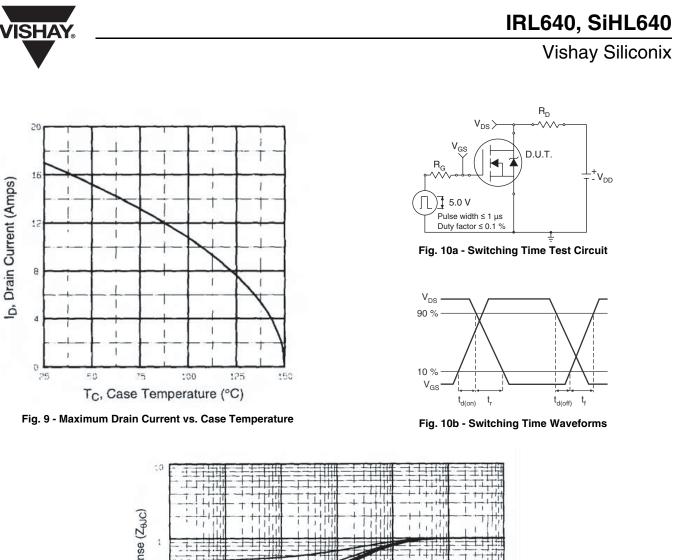
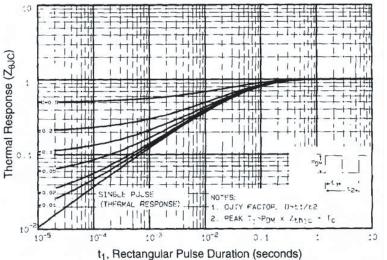
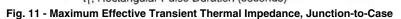


Fig. 8 - Maximum Safe Operating Area







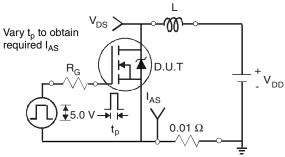


Fig. 12a - Unclamped Inductive Test Circuit

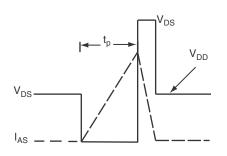


Fig. 12b - Unclamped Inductive Waveforms

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τν_{dd}

t,

t_{d(off)}

 R_D

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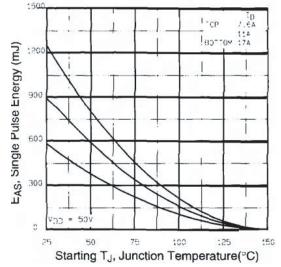


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

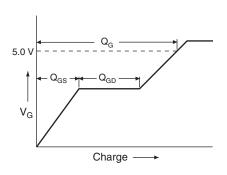


Fig. 13a - Basic Gate Charge Waveform

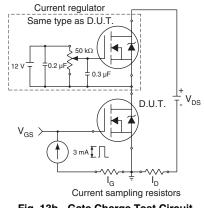
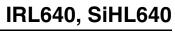
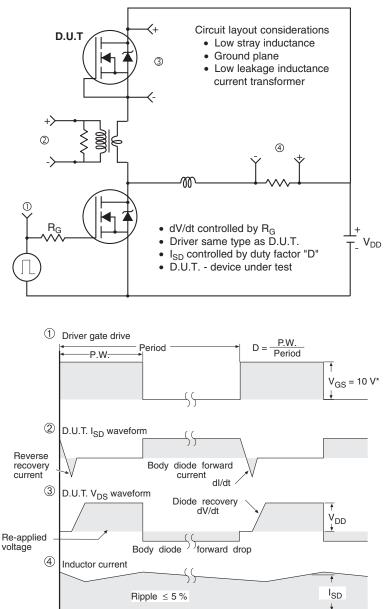


Fig. 13b - Gate Charge Test Circuit







Peak Diode Recovery dV/dt Test Circuit

* V_{GS} = 5 V for logic level devices

Fig. 14 - For N-Channel

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